

**Search Notes**

Application/Control No.

10/082,176

Examiner

Tse Chen

Applicant(s)/Patent under  
Reexamination

HASEGAWA, TOSHITAKA

Art Unit

2116

**SEARCHED**

Class	Subclass	Date	Examiner
713	300	8/13/2007	TC
713	330	8/13/2007	TC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
713	300	8/13/2007	TC
713	330	8/13/2007	TC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
713/300 and 713/330 with "random arbitrary" near "offset margin"	8/13/2007	TC